

Product Change Notification - JAON-26AJLN058

Date:

28 Feb 2020

Product Category:

Ethernet Switches

Affected CPNs:



Notification subject:

CCB 3867.001 Final Notice: Qualification of ASE as a new assembly site for selected Micrel KSZ8893 device family available in 100L LFBGA (9x9x1.38 mm) package.

Notification text:

PCN Status:

Final notification

PCN Type:

Manufacturing Change

Microchip Parts Affected:

Please open one of the icons found in the Affected CPNs section above.

NOTE: For your convenience Microchip includes identical files in two formats (.pdf and .xls).

Description of Change:

Qualification of ASE as a new assembly site for selected Micrel KSZ8893 device family available in 100L LFBGA (9x9x1.38 mm) package.

Pre Change:

Assembled at OSE assembly site using 2300 die attach and E770 molding compound.

Post Change:

Assembled at ASE assembly site using 2100A die attach and KE-G1250NAS molding compound.

Pre and Post Change Summary:

		Pre Change	Post Change	
Assembly Site		Orient Semiconductor	Advanced Semiconductor	
		Electronics, Ltd (OSE)	Engineering, Inc. (ASE)	
Wire m	naterial	Au	Au	
Die attach material		2300	2100A	
Molding comp	oound material	E770	KE-G1250NAS	
	Core	HL832NX	HL832NX	
Substrate	Solder Mask	AUS308	AUS308	
material	Solder Mask Thickness	25 ± 10µm	30 ± 10µm	
Solder Ball		SAC305	SAC305	

Impacts to Data Sheet:

None

Change Impact:

None

Reason for Change:

To improve manufacturability by qualifying ASE as a new assembly site.

Change Implementation Status:

In Progress

Estimated First Ship Date:



April 17, 2020 (date code: 2016)

NOTE: Please be advised that after the estimated first ship date customers may receive pre and post change parts.

Time Table Summary:

	February 2020		->	April 2020						
Workweek	6	7	8	9		14	15	16	17	18
Qual Report Availability				X						
Final PCN Issue Date				Χ						
Estimated Implementation Date								X		

Method to Identify Change:

Traceability code

Qualification Report:

Please open the attachments included with this PCN labeled as PCN # Qual Report.

Revision History:

February 28, 2020: Issued final notification. Attached the qualification report. Provided estimated first ship date to be on April 17, 2020.

The change described in this PCN does not alter Microchip's current regulatory compliance regarding the material content of the applicable products.

Attachment(s):

PCN JAON-26AJLN058 Qual Report.pdf

Please contact your local <u>Microchip sales office</u> with questions or concerns regarding this notification.

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JAON-26AJLN058 - CCB 3867.001 Final Notice: Qualification of ASE as a new assembly site for selected Micrel KSZ8893 device family available in 100L LFBGA (9x9x1.38 mm) package. Affected Catalog Part Numbers (CPN) KSZ8893MBL KSZ8893MBLI KSZ8893MBL-TR

Date: Friday, February 28, 2020



QUALIFICATION REPORT SUMMARY

PCN #: JAON-26AJLN058

Date:

January 6, 2020

Qualification of ASE as a new assembly site for selected Micrel KSZ8842 device family available in 100L LFBGA (9x9x1.38 mm) package. The qualification for selected Micrel KSZ8893 device family available in 100L LFBGA (9x9x1.38 mm) package will qualify by similarity (QBS).

Purpose:

Qualification of ASE as a new assembly site for selected Micrel KSZ8842 device family available in 100L LFBGA (9x9x1.38 mm) package. The qualification for selected Micrel KSZ8893 device family available in 100L LFBGA (9x9x1.38 mm) package will qualify by similarity (QBS).

I. Summary:

The purpose of this report is to qualify Mask #TARA1 (KSZ8842PMBL-AM) in LFBGA 9x9x 1.38 mm, 100 pins package at ASE, per CCB# 3867, following AEC-Q100 and guidelines established in Microchip specification QCI-39000, "Worldwide Quality Conformance Requirements".

II. Conclusion:

Based on the results, Mask #TARA1 (KSZ8842PMBL-AM) in LFBGA 9x9x 1.38 mm, 100 pins package at ASE package complies with the reliability guidelines implemented in the qualification plan. Therefore, the LFBGA from ASE qualified for Q100 Grade 3 package for TARA1 product family.

III. Device Description:

Device	KSZ8842PMBL-AM
MPC	TARA17ABAA02
Mask	TARA1
Document Control Number	ML012020002O
Document Revision	A
CCB No.	3867 and 3867.001

IV. Qualification Material:

Test Lot	Lot 1	Lot 2	Lot 3
ASSEMBLY LOT	ASE201600282.000	ASE201600283.000	ASE201600286.000
PACKAGE	100L-LFBGA9x9x 1.38mm	100L-LFBGA9x9x 1.38mm	100L-LFBGA9x9x 1.38mm
ASSEMBLY SITE	ASE, Taiwan	ASE, Taiwan	ASE, Taiwan
FINAL TEST LOCATION	OSE, Taiwan	OSE, Taiwan	OSE, Taiwan
QUAL TESTS	PRECOND, HTSL, HAST, UHAST, TC	PRECOND, HAST, UHAST, TC	PRECOND, HAST, UHAST, TC

V. Bill of Materials:

	The Vallage Amany				
	Assembly site	ASE			
	BD Number	AAH@A271280002-0			
Misc.	MP Code (MPC)	TARA17ABAA02			
	Part Number (CPN)	KSZ8842-PMBL-AM			
	MSL information	MSL3 / 260			
	Core Material	HL832NX			
	Core Thickness	200um			
<u>Substrate</u>	L1/L2 Thickness	18um			
<u>Sussiture</u>	SM Material	AUS308			
	Process	Normal			
	SM Thickness	30+/-10			
Bond Wire	Material	Au			
Die Attach	Part Number	2100A			
<u> </u>	Conductive	Yes			
<u>MC</u>	Part Number	KE-G1250NAS			
	PKG Type	LFBGA			
	Pin/Ball Count	100			
<u>PKG</u>	PKG width/size	9x9x1.38mm			
	Ball Pitch/Size	0.8mm / 0.45mm			
	Solder Ball Material	SAC305			

VI. Qualification Data:

Package Preconditioning

Test Method/Condition	JEDEC J-STD-020D and JESD22-A113F,
	MSL Level 3 soak and 260°C peak Reflow Temperature
Lot #	Results (Fail/Pass)
Lot 1	0/255
Lot 2	0/255
Lot 3	0/255

HAST (Highly Accelerated Temperature and Humidity Stress Test)

Test Method/Condition	JESD22-A110, Vin = +3.3V, Ta = +130°C/85%RH, 96 HRS
	Min SS = 77 units
Lot #	Results (Fail/Pass)
Lot 1	0/82 @ 96 hrs
Lot 2	0/82 @ 96 hrs
Lot 3	0/82 @ 96 hrs

Pre and Post testing was conducted at +25°C, +85°C

UNBIASED HAST

Test Method/Condition	JESD22-A118, Ta = +130°C/85%RH, 96HRS
	Min $SS = 77$ units
Lot#	Results (Fail/Pass)
Lot 1	0/82 @ 96 hrs
Lot 2	0/82 @ 96 hrs
Lot 3	0/82 @ 96 hrs

Post testing was conducted at +25°C

Temperature Cycling

remperature Syeming	
Test Method/Condition	JESD22-A104, Ta = -55°C/+125 °C, 500 CYC
	Min SS = 77 units
Lot #	Results (Fail/Pass)
Lot 1	0/82 @ 500 cycles WBP: 0 fails/5
Lot 2	0/82 @ 500 cycles
Lot 3	0/82 @ 500 cycles

Pre and Post testing was conducted at +85°C

High Temperature Storage Life

Test Method/Condition	JESD22-A103, Ta = +150 °C, 500 HRS
	Min SS = 45 units
Lot #	Results (Fail/Pass)
Lot 1	0/50 @ 500 hrs

Pre and Post testing was conducted at +25°C, +85°C

VII. Wire Pull/Ball Shear

Lot #1:

Test Item	Sample	Comment
	Size/ Unit	
Wire Pull	30 wires	Pass
Ball Shear	40 balls	Pass
Solder Ball Shear	60 balls	Pass

Lot #2

Test Item	Sample	Comment
	Size/ Unit	
Wire Pull	30 wires	Pass
Ball Shear	40 balls	Pass
Solder Ball Shear	60 balls	Pass

Lot #3

Test Item	Sample	Comment
	Size/ Unit	
Wire Pull	30 wires	Pass
Ball Shear	40 balls	Pass
Solder Ball Shear	60 balls	Pass

VIII. Physical Dimension:

Test Method/Condition	JESD22 -B100 and B108, Min SS = 10 units/lot
Lot#	Results (Fail/Pass)
Lot 1	0/10 PASS
Lot 2	0/10 PASS
Lot 3	0/10 PASS